



FOR IMMEDIATE RELEASE

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**AEHR TEST SYSTEMS RECEIVES MULTI-MILLION DOLLAR
REPEAT ORDERS FOR MAX BURN-IN AND TEST SYSTEMS**

Fremont, CA (February 28, 2006) – Aehr Test Systems (Nasdaq: AEHR), a leading supplier of semiconductor test and burn-in equipment, today announced it received over \$4 million in repeat orders during the Company’s third fiscal quarter for its MAX burn-in and test systems from a leading semiconductor IC manufacturer. The systems are expected to ship during the next six months.

“We are very excited about these orders,” said Greg Perkins, vice president of sales and service of Aehr Test Systems. “Many of the orders are being driven by an increasing need for semiconductor ICs used in automotive applications. A key feature of the MAX systems being ordered is the ability to do monitored burn-in. This capability insures that all devices are fully stressed during the burn-in process. This results in extremely high reliability for these devices that are being used in automobiles and high-end consumer products.

“As the automotive industry makes more and more use of electronics in everything from mapping systems to engine control to brake systems, there will be an increasing demand for higher and higher reliability for the components that are used. In order to meet the stringent reliability requirements of the automotive market, many IC manufacturers do a 100% burn-in of all their automotive products,” said Mr. Perkins.

About Aehr Test Systems

Headquartered in Fremont, California, Aehr Test Systems is a leading worldwide provider of systems for burning-in and testing DRAM and logic integrated circuits and has an installed base of more than 2,500 systems worldwide. Aehr Test has developed and introduced several innovative products, including the FOX™, MTX and MAX systems and the DiePak® carrier. The FOX system is a full wafer contact test and burn-in system. The MTX system is a massively parallel test system designed to reduce the cost of memory testing by performing both test and burn-in on thousands of devices simultaneously. The MAX system can effectively burn-in and functionally test complex devices, such as digital signal processors, microprocessors, microcontrollers and systems-on-a-chip. The DiePak carrier is a reusable, temporary package that enables IC manufacturers to perform cost-effective final test and burn-in of bare die. For more information, please visit the Company’s website at www.aehr.com.

Safe Harbor Statement

This release contains forward-looking statements that involve risks and uncertainties relating to projections regarding customer demand and acceptance of Aehr Test's products. Actual results may vary from projected results. These risks and uncertainties include, without limitation, acceptance by customers of the MAX technology, acceptance by customers of the MAX systems shipped upon receipt of a purchase order and the ability of new products to meet customer needs or perform as described. See Aehr Test's recent 10-K and 10-Q reports and other reports from time to time filed with the Securities and Exchange Commission (SEC) for a more detailed description of the risks facing our business. The Company disclaims any obligation to update information contained in any forward-looking statement to reflect events or circumstances occurring after the date of this press release.

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